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AMPMODU*, MOD II INTERCONNECTION SYSTEM, 2.54mm [.100 in.] PITCH

1. SCOPE

- 1.1. This specification covers performance and test requirements for the AMPMODU*, MOD II interconnection system, 2.54mm pitch (Italian range)
- 1.2. When tests or inspections are performed on the subject product line, this document should always be used together with the applicable product drawings.

2. DESCRIPTION

This system provides wire to board and board to board termination at 2.54mm [.100 in] pitch using the 0.63x0.63mm [.025 sq. in.] post technology.

It is composed of:

2.1. Crimped receptacle connector:

Single and double row, having standard and high-pressure contacts for discrete wires covering a range of 22 to 30 AWG (0.04mm² to 0.5mm²)

2.2. Board mount receptacle connector assembly:

Single and double row, horizontal and vertical mount, having standard or high-pressure receptacle contacts inserted into an insulated housing which is directly mounted on a printed circuit.

2.3. Header assembly:

Single or double row, having straight or right-angle post contacts inserted into an insulated header which is directly mounted on a printed circuit board.

3. APPLICABLE DOCUMENTS

Applicable portion of the following documents form a part of this specification, to the extent indicated herein. Unless otherwise indicated the latest edition of the document applies.

In the event of conflict between the requirements of this specification and the product drawing, the product drawing shall take precedence.

3.1. Industry Standard

•	IEC 60512-2:	Electrochemical components for electronic equipment:
		Basic testing procedures and measuring methods

- IEC 60130-1: Connectors for frequencies below 3MHz, general requirements and
 - Measuring methods
- IEC 60068-2: Basic environmental testing procedures for electronic equipment and Components
- UNI 5085: Corrosion test of protective metallic coatings (Kesternich test)



4. **REQUIREMENTS**:

4.1 Design and construction:

All components of this product line shall be of the design, construction and physical dimensions specified in the applicable product drawings.

- 4.2 Materials:
 - Receptacle contact: Copper alloy, pre-gold plated (0.38 or 0.76μm) over Nickel or pre-tin Plated (0.76μm) over Nickel
 - Post contact: Copper alloy, gold plated (0.38 or 0.76μm Duplex plating) over Nickel or tin plated (2.0 μm min.) over Nickel
 - Receptacle housings: LCP, Flammability rating UL 94V-0
 - Receptacle board mounted housings; LCP, Flammability rating UL 94V-0
 - Shrouded header housings; PBT, Flammability rating UL 94V-0
 - Pin housings single row: LCP, Flammability rating UL 94V-0
 - Pin housings dual row: Polyphenylene Oxide (Noryl), Flammability rating UL 94V-1

4.3 Ratings:

- A. Current: 3A max per contact
- B. Operating temperature: -40°C to +80°C
- C. Climate category (IEC): 40/80/21
- D. Max. Operating voltage: 40 Vac or Vdc

For application at higher voltage, please contact TE

5. PERFORMANCE AND TEST DESCRIPTION

This product line shall meet the electrical, mechanical and environmental performance requirements specified in following table

TEST DESCRIPTION	TEST PROCEDURE	REQUIREMENTS		
Initial examination of product	Visual, dimensional and functional check	Shall be in accordance with the relevant product drawings		
Total connection	According to IEC 60512-2-1 (test 2a).	15mΩ max.		
resistance, low level (Dry circuit)	Subject mated contacts assembled in housing to 20mV max (Open circuit) at 20mA and measure as indicated in fig. 1a and 1b.			
	Calculate the termination resistance, subtracting the resistance of wire.			
Crimp resistance, low	According to IEC 60512-2-1 (test 2a).	7mΩ max.		
level (Dry circuit)	Subject mated contacts to 20mV max (Open circuit) at 20mA and measure as indicated in fig. 2			
	Calculate the crimp resistance, subtracting the resistance of the wire.			
Insulation resistance	According to IEC 60512-3-1 (test 3a).	Initial : 5000m Ω min		
	Two between adjacent or opposite contact of mated connectors by applying 500V dc for 1 min.	Final : $1000m\Omega$ min		



TEST DESCRIPTION		TEST PROCE	REQUIREMENTS				
Dielectric Withstanding	According to IE	C 60512-4-1(tes	No breakdown or flashover				
voltage	mated						
Engaging force	ngaging force According to IEC 60512-13-2 (test 13b)						
	a) <u>With gage:</u> m	neasure force to	Std Pr. : 1.8 N max				
	b) With posts: n	neasure force ne	High Pr. : 5.0 N max				
	and female con locking device,	nector assembli using a suitable	Std Pr. : 2.0 N max				
	Calculate force	per contact.			High Pr. : 7.0 N max		
Separating force	According to IE	C 60512-13-2 (te	est 13b)		Initial values:		
	Measure force t	o separate using	g a steel gage s	ize 2,	Std Pr. : 0.4 N min		
	as indicated in I	Fig 3.			High Pr. : 0.6 N min		
					After durability :		
					Std Pr. : 0.35 N min		
Durability	According to IE	C 60512-9-1 (te		No physical damage.			
	Mate and un-ma assemblies usir		Shall meet the requirements of subsequent tests listed in				
	Number of cycle	es:			para 6		
	Туре	Plating	Cycles				
	Std. Pr.	0.38µm gold	100				
	Std. Pr.	0.76µm gold	200				
	High Pr.	0.76µm tin	25				
Crimp tensile	According to IE	C 60512-16-4 (te	75% min. of tensile strength				
	Determine crim wire , at a rate o	p tensile, by app of 25mm/min.	of wire.				
Contact retention		30 N min.					
	According to IE	C 60512-15-1 (te	est 15a).				
	Apply an axial le housing.	oad to crimped o					
Locking device retention	To be performe applying an axia	d on plastic hou al load to mated	5 N min.				
Vibration	According to IE	C 60512-6-4(tes		No physical damage.			
	Subject mated of	connectors to 10	No discontinuities greater				
	Displacement: 1	1.5mm (max tot)					
	Sweep time: 15	min.					
	No of cycles: 12						

TEST DESCRIPTION	TEST PROCEDURE	REQUIREMENTS		
Corrosion, salt spray	sion, salt spray According to IEC 60512-11-6 (test 11f). Subject mated connectors to 48 hours of salt spray, with 5% of NaCl concentration.			
Corrosion, Kesternich test	Corrosion, Kesternich test Subject mated and unmated connectors to the Kesternich test, according to UNI 5085 Duration of test : 8 hours			
Thermal shock	According to IEC 60512-11-4(test 11d).	No physical damage.		
	Subject mated connectors to 5 cycles between -40°C to +80°C. Lasting time to each temperature : 30 min.	Shall meet the requirements of subsequent tests listed in para 6.		
Damp heat, steady state	According to 60512-11-3 (test 11c).	No physical damage.		
	Subject mated connectors to 21 days of damp heat, at a temperature of 40°C and 96% of relative humidity	Shall meet the requirements of subsequent tests listed in para 6.		
Temperature/Humidity	According to IEC 60068-2-38, test Z/AD	No physical damage.		
cycling	Subject mated connectors to 10 temperature/humidity cycles. Duration of each cycle : 24h	Shall meet the requirements of subsequent tests listed in para 6.		
Solderability	Post contacts mated with relevant printed circuit boards.	At least 95% of soldering area of tested post contacts		
	According to IEC 60068-2-20, test Ta, method 1: solder bath at 235°C	shall have a fresh, smooth and uniform coverage of		
	Samples shall be previously aged by subjecting to Damp heat test with 85°C and 85% humidity for 4 days.			
	(Simulates 2 years of Solderability)			



NOTE

Shall meet visual requirements, show no physical damage, and meet requirements of additional tests as specified in the Product Qualification and Requalification Test Sequence shown in para 6.



6. PRODUCT QUALIFICATION AND REQUALIFICATION TEST SEQUENCE

	TEST GROUP							
TEST OR EXAMINATION	1	2	3	4	5			
		TEST SEQUENCE						
Examination of product	1, 10	1, 10	1, 7	1, 3	1, 7			
Termination resistance	2, 9	4, 9						
Crimp resistance (a)								
Insulation resistance		2, 6	2, 5		2, 5			
Dielectric withstanding voltage		3, 7	3, 6		3, 6			
Engaging force	3, 6							
Separating force	4, 7							
Durability	5							
Crimp tensile (a)								
Contact retention (a)								
Locking device retention (a)								
Corrosion, salt spray (b)	8							
Corrosion, Kersternich test (b)	8							
Thermal shock		5						
Damp heat, steady state					4			
Temperature humidity cycling			4					
Solderability				2				
Vibration		8						



NOTE

- (a) Tests to be performed on separate samples (not in sequence)
- (b) Alternative test methods



7. QUALIFICATION TEST

Qualification test shall be performed according to test methods and requirements specified in para 5 and test sequence specified in para 6.

Samples shall be selected at random from current production.

Each test group shall consist of 4 connectors



a) Board to board version



b) Wire to board version







FIG 2 - Crimp Resistance measurement set-up



NOTES :

1. Material :

Stainless steel, heat treated ; Hardness : 60+62 HRC

2. Surface roughness:

0.1 μm Ra on all sides

GAGE	A (mm)	A (inches)
1	0.6604 +0.0000 -0.0025	.0260 ^{+.0000} 0001
2	0.6096 ^{+0.0025} -0.0000	.0240 +.0001 0000

FIG. 3 - Engaging / Separating force gages

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